Templating Highly Crystalline Organic

Semiconductors using Atomic Membranes of

Graphene at the Anode/Organic Interface

Susmit Singha Roy, Dominick J. Bindl, Michael S. Arnold*

Department of Materials Science and Engineering, University of Wisconsin - Madison

1509 University Avenue, Madison, Wisconsin 53706, United States

Email Address: msarnold@wisc.edu

SUPPORTING INFORMATION

The peaks positions of the XRD spectra were independent of film thickness over the

explored range of 20 nm to 320 nm (as shown in Figure S1), indicating that the orientation of the

CuPc was invariant over this range.

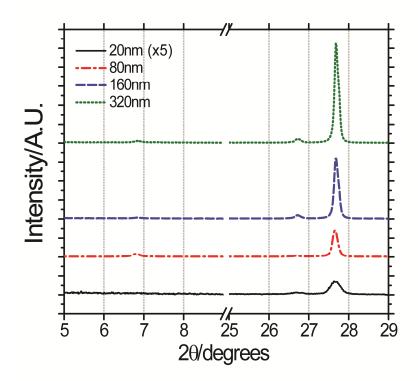


Figure S1. X-ray diffraction of CuPc on GMG for CuPc film thicknesses of 20 nm (solid/black) 5x magnification, 80 nm (dot-dashed/red), 160 nm (dashed/blue) and 320 nm (dotted/green), offset for clarity.